

Search Notes



Application/Control No.

10/717,284

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

TAFT ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	541	10.18.04	162
	539	↓	↓
	540		
	391	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	06.17.05	162